



Session Title:	[WeG1] Frontier Metrology and Modeling III
Session Date:	November 13 (Wed.), 2024
Session Time:	09:10-10:40
Session Room:	Room G (Meeting Room, 5F, Grand Josun Busan)
Session Chair:	Prof. Sung Beom Cho (Ajou Univ., Korea)

[WeG1-1] [Invited] 09:10-09:40

Advancements in Metrology for Materials and Device Characterization: Exploring Innovative In-Materials Processing Techniques for Emerging Applications

Mohit Kumar and Hyungtak Seo (Ajou Univ., Korea)

[WeG1-2] [Invited] 09:40-10:10

Data Intelligence for Semiconductor Autonomous Fab

Younghoon Sohn (Samsung Electronics Co., Ltd., Korea)

[WeG1-3] [Invited] 10:10-10:40

Semiconductor Electronic Structure Measurement by Photoelectron Spectroscopy

Jeong Won Kim (KRISS, Korea)